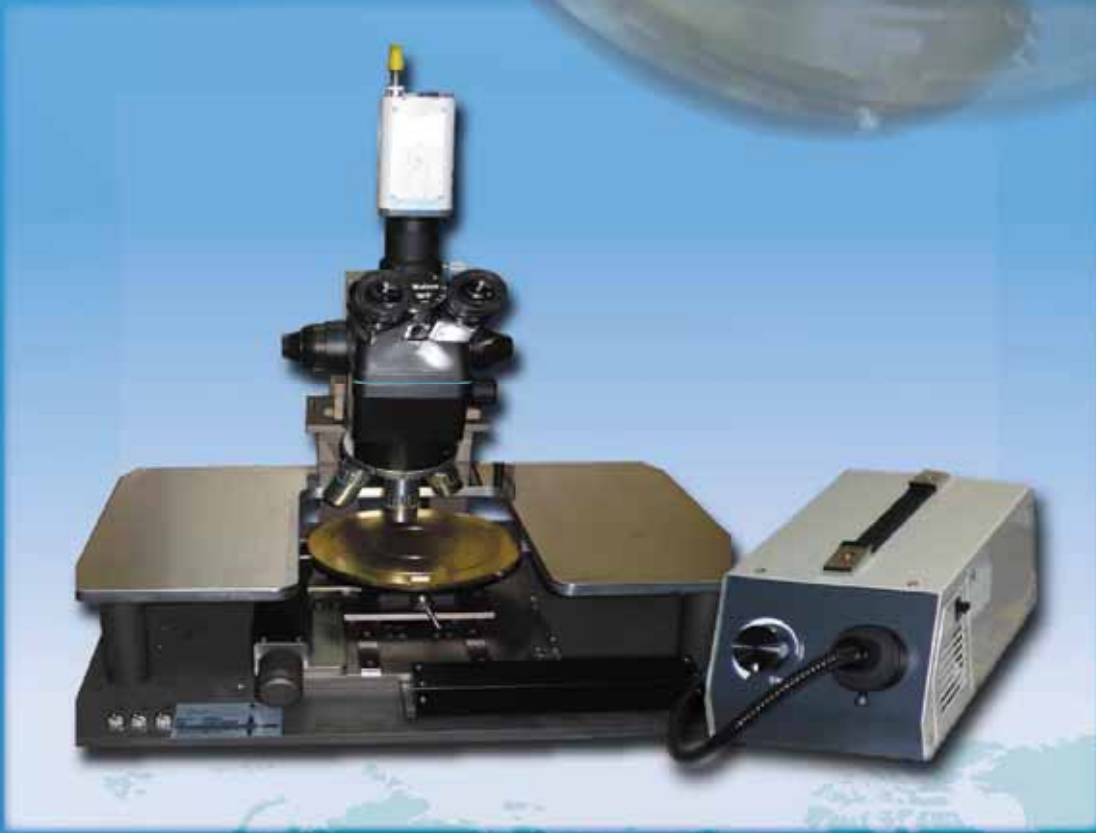




ANALYTICAL PROBE STATION

MICROTEST
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Email : microtest@microtest-semi.com
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APS 150/200



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Sup



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APS Series Probe Station (APS 150/200)

Features

- Hugel-Knob Chuck stage
- Ball Screw Driven Chuck Stage
- RF Probing Field Upgradeable
- Backlash-Free Movement
- High Magnification Microscope Compatible

Specifications

- Vacuum chuck : 150mm/ 200mm stainless steel
- Chuck stage travel :
 - APS 150 : 150mm x 150mm
 - APS 200 : 200mm x 200mm
- Chuck theta : 0~30degree
- Chuck up / down : 5mm
- Microscope stage travel : 25 x 25mm
- Platen movement : fixed
- Sample Size: 5x5mm ~ 150 / 200mm
- Chuck Flatness: 10um



Dimensions

- Dimension(W/D/H) :
 - APS 150 : 580mm x 460mmD x 700mm
 - APS 200 : 660mm x 660mmD x 700mm
- Weight : 60kg (APS 150) , 80kg (APS 200)

Options

- Gold Plated Vacuum Chuck
- Thermal Systems
- Chuck Vacuum Pattern
- Pneumatic microscope lift for objective changer over
- RF Probes/Cables
- Active Probes
- Low Current/Capacitance Probes
- High Voltage Probes
- Laser Cutter
- CCD/Digital Camera with USB Connection
- Vibration Free Table
- Shielding Box
- Instrument Case with Caster



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飛白技術服務股份有限公司

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